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SPC-F005.DWG

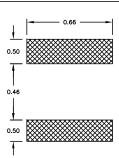
	REVISIONS			0. SPC-F005	* Effe	ctive: 7/8/0	2 * DCF	No: 1398
DCP #	CP # REV DESCRIPTION		DRAWN	DATE	CHECKD	DATE	APPRVD DATE	
2048	Α	RELEASED	JN	05/21/09	JWM	05/21/09	JWM	05/21/09



#### Features:

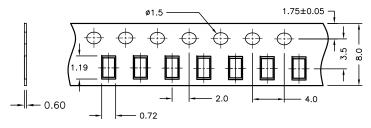
- Wire wound ceramic construction provide high SRF
- Ultra-compact inductors provide exceptional Q values
- Low profile, high current are available
- Miniature SMD chip inductor for fully autmated assembly
- Outstanding endurance from Pull-up force, mechanical shock and pressure
- tighter tolerance down to ±2%

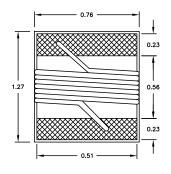
#### **Recommended Pad Layout**

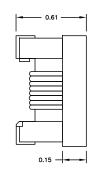




## **Tape & Reel Dimension**







DISCLAIMER:
ALL STATEMENTS AND TECHNICAL INFORMATION CONTAINED
HEREIN ARE BASED UPON INFORMATION AND/OR TESTS WE
BELIEVE TO BE ACCURATE AND RELIABLE. SINCE
CONDITIONS OF USE ARE BEYOND OUR CONTROL, THE
USER SHALL DETERMINE THE SUITABILITY OF THE PRODUCT
FOR THE INTENDED USE AND ASSUME ALL RISK AND
LIABILITY WHATSOEVER IN CONNECTION THEREWITH.

TOLERANCES:

DRAWN BY:	DATE:
Jason Nash	05/21/09
CHECKED BY:	DATE:
JWM	05/21/09
APPROVED BY:	DATE:
JWM	05/21/09

	DRAW	ING TITLE:						
09	Wire Wound Chip Inductor — Case size 0402							
	SIZE	DWG. NO.			ELEC	TRONIC FIL	E	REV
09	Α	A Ta-1116			Ta	-1116.	DWG	Α
09	SCAL	E: NTS		U.O.M.: Millimeters		SHEET:	1 01	- 3



Mfr PN	Inductance	Inductance Tolerance	DC Resistance Max	DC Current Rating	Self Resonant Frequency	Package	Q Factor	Test Frequency
MCWL02JT10N	10nH	± 5%	0.195ohm	480mA	3.90MHz	402	Q Factor:21	250MHz
MCWL02JT12N	12nH	± 5%	0.120ohm	640mA	3.60MHz	402	Q Factor:24	250MHz
MCWL02JT15N	15nH	± 5%	0.172ohm	560mA	3.28MHz	402	Q Factor 24	250MHz
MCWL02JT18N	18nH	± 5%	0.230ohm	420mA	3.10MHz	402	Q Factor:25	250MHz
MCWL02JT22N	22nH	± 5%	0.300ohm	400mA	2.80MHz	402	Q Factor 25	250MHz
MCWL02JT27N	27nH	± 5%	0.300ohm	400mA	2.48MHz	402	Q Factor:24	250MHz
MCWL02JT33N	33nH	± 5%	0.350ohm	400mA	2.35MHz	402	Q Factor:24	250MHz
MCWL02JT39N	39nH	± 5%	0.550ohm	200mA	2.10MHz	402	Q Factor:25	250MHz
MCWL02JT47N	47nH	± 5%	0.830ohm	150mA	2.10MHz	402	Q Factor:25	250MHz
MCWL02JT56N	56nH	± 5%	0 <u>.</u> 970ohm	100mA	1.76MHz	402	Q Factor 25	250MHz
MCWL02JT68N	68nH	± 5%	1.120ohm	100mA	1.62MHz	402	Q Factor:22	250MHz
MCWL02JT6N8	6.8nH	± 5%	0.083ohm	680mA	4.80MHz	402	Q Factor:20	250MHz
MCWL02KT1N0	1nH	± 10%	0.045ohm	1360mA	12.70MHz	402	Q Factor:16	250MHz
MCWL02ST2N2	2.2nH	± 5%	0.070ohm	960mA	10.80MHz	402	Q Factor:19	250MHz
MCWL02ST3N3	3.3nH	± 5%	0.066ohm	840mA	7.00MHz	402	Q Factor:19	250MHz
MCWL02ST4N7	4.7nH	± 5%	0.130ohm	640mA	4.70MHz	402	Q Factor:18	250MHz

### **Mechanical Performance**

No.	Item	Specification	Test Methods				
1	VIbration Test	Appearance: No damage L change: within ±5% Q change: within ±10%	Test device shall be soldered on the substrate Oscillation Frequency: 10 to 55 to 10Hz for 1mln Amplitude: 1.5mm Time: 2hrs for each axis (X, Y &Z), total 6hrs				
2	Resistance to Soldering-Heat	we change. Within 210%	Solder Temperature: 270±5°C Immersion Time: 10±2sec				
3	Component Adhesion (Push Test)	1 lbs. For 0402 2 lbs. For 0603 3 lbs. For the rest	The device should be soldered (280±5°C for 10 seconds) to a tinned copper subs rate. A dynamiter force gauge should be applied to the side of the component. The device must with stand a minimum force of 2 or 4 pounds without a failure of adhesion on termination				
4	Drop Test	No damage	Dropping chip by each side and each corner. Drop 10 times in total Drop height: 100cm Drop weight: 125g				
5	Solderability Test	90% covered with solder.	Inductor shall be dipped in a melted solder bath at 245±5°C for 3 seconds.				
6	Resistance to Solvent Tes	No damage on appearance and marking.	MIL-STD202F, Method 215D				

### **Electrical Performance Test**

No.	item	Specification	Test Method				
1	Inductance		HP4291B				
2	Q		HP4291B				
3	SRF	Refer to standard electrical	HP8753D				
4	DC Resistance RDC	characteristic spec.	Micro-Ohm meter (Gom-801G)				
5	Rated Current IDC		Applied the current to colls, The Inductance change should be less than 10% to initial value				
6	Over Load Test	Inductors shall have no evidence of electrical and mechanical damage	Applied 2 times of rated allowed DC current to inductor for a period of 5 mlnute				
7	Withstanding Voltage Test	Inductors shall be no evidence of electrical and mechanical damage.	AC voltage of 500 VAC applied between inductors terminal and case for 1 minute.				
8	Insulation Resistance Test	1000M ohm min	100 VDC applied between inductor terminal and case				

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		A   Ta-1116   Ta-1		ı-1116.DWG	Α			
SPC-F005.DWG	DOC. NO. SPC-F005 * Effective: 7/8/02 * DCP No: 1398	SCALE	E: NTS	U.O.M.: INCHES [mm]	]	SHEET: 2 OF	F 3	



# **Climatic Test**

No.	Item	Specification	Test Method				
1	Temperature Characteristic		-40°C +125°C				
2	Humidity Test		Temperature: 40±2°C Relative Humidity: 90~95% Time: 96hrs±2hrs Measured after exposure in the room condition for 2hrs Temperature: -40±2°C Time: 96±2hrs Inductors are tested after 1 hour at room temperature				
3	Low Temperature Storage Test	Appearance: No damage L change: within ±10%					
4	Q change: within ±20%  [hermal Shock Test]	One cycle:           Step         Temperature         Time (min)           1         -25±3         30           2         25±2         15           3         125±3         30           4         25±2         15           Total: 5 cycles					
5	High Temperature Storage Test	ge	Temperature:125±2 Time: 96±2hrs Measured after exposure in the room condition for 1hr				
6	High Temperature Load Life Test	There should be no evidence of	Temperature:85±2 Time:1000±12hrs Load: Allowed DC current				
7	Humidity Load Life	short of open circuit.	Temperature: 40±2C Relative Humidity: 90~95% Time: 1000±12hrs Load: Allowed DC current				

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EXPRESS WRITTEN CONSENT OF SPC TECHNOLOGY.	IN THE PART OF THE	A	Ta-	-1116	Ta	-1116.DWG	A
SPC-F005.DWG	DOC. NO. SPC-F005 * Effective: 7/8/02 * DCP No: 1398	SCALE	: NTS	U.O.M.: INCHES [mm]		SHEET: 3 0	F 3